

MOS-FET

IGBT

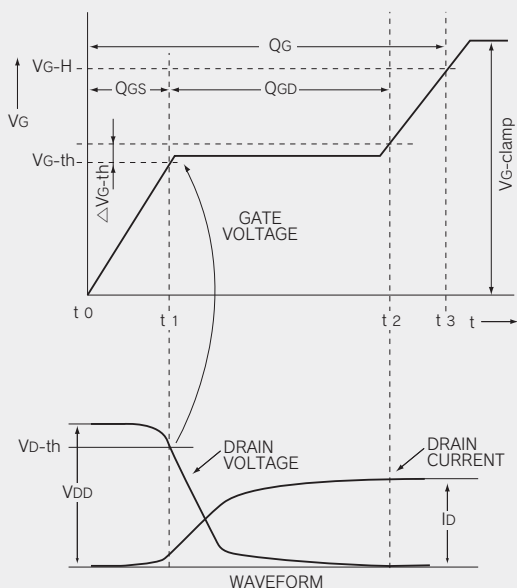
SWITCHING TIME & QG TEST SYSTEM スイッチングタイム&ゲート容量テストシステム

SWQR550 500V 50A

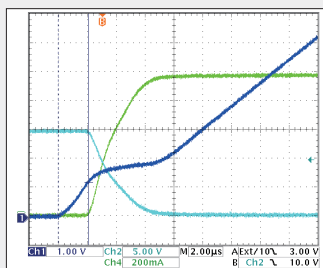


- SWQR550 has both function of resistive load switching time and gate capacity (QG) measurement. However, it can not measure resistive load switching time and gate capacity consecutively because each measurement characteristic is respected.
- SWQR550はR負荷スイッチングタイム測定のほか、ゲート容量(QG)測定機能を併せ持っています。ただし、各測定の特性を重視しているため、R負荷スイッチングとゲート容量の連続測定は行えません。

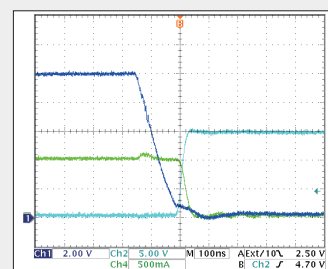
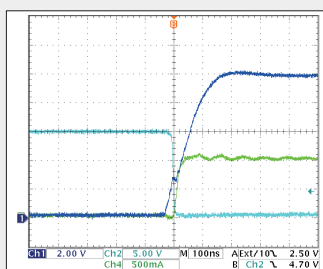
Measurement Waveform (QG)



Measurement Waveform (QG)



Measurement Waveform (R-Switching)



MODEL

SWQR550

SETTING RANGE(R-SWITCHING)

MEASURABLE DEVICES	N/P MOS-FET, N/P IGBT
TEST ITEM	td/td(on), tr, tstg/td(off), tf, Eon, Eoff
MEASUREMENT RANGE	0.1ns~10μs
VDD	1V~500V 1V STEP
Id(Limit)	0.1A~50.0A 0.1A STEP
Vgf	0.0V~20.0V 0.1V STEP [Maximum pulse current 1A] [最大ノルス電流1A]
Vgr	0.0V~20.0V 0.1V STEP [Maximum pulse current 1A] [最大ノルス電流1A]
ON TIME/OFF TIME	1μs~100μs 1μs STEP
REPEAT	1~10

SETTING RANGE(QG)

TEST ITEM	Vg-th, QGs, QGd, QG
MEASUREMENT RANGE	Vg-th : 00.0V~19.9V QGs/QGd: 000.00nC~199.99nC QG : 000.00nC~499.99nC
IC/Id	MAX 50A Measuring by VDD/Resistive load (VDD/R負荷により測定)
Vcc/VDD	1V~500V 1V STEP
IG	0.01mA~9.99mA 0.01mA STEP
VG-CLAMP	1V~20V 1V STEP

BINNING

OPEN/SHORT CHECK	VGF ON : VCE/VDS ≥ 1/2 VDD...OPEN VGF OFF : VCE/VDS ≤ 1/2 VDD...SHORT
BIN INDICATION	PASS, ERROR, LIMIT-FAIL, OPEN/SHORT

DIMENSIONS & WEIGHT

MAIN UNIT	550(W)×860+400(D)×1700(H)…272kg
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